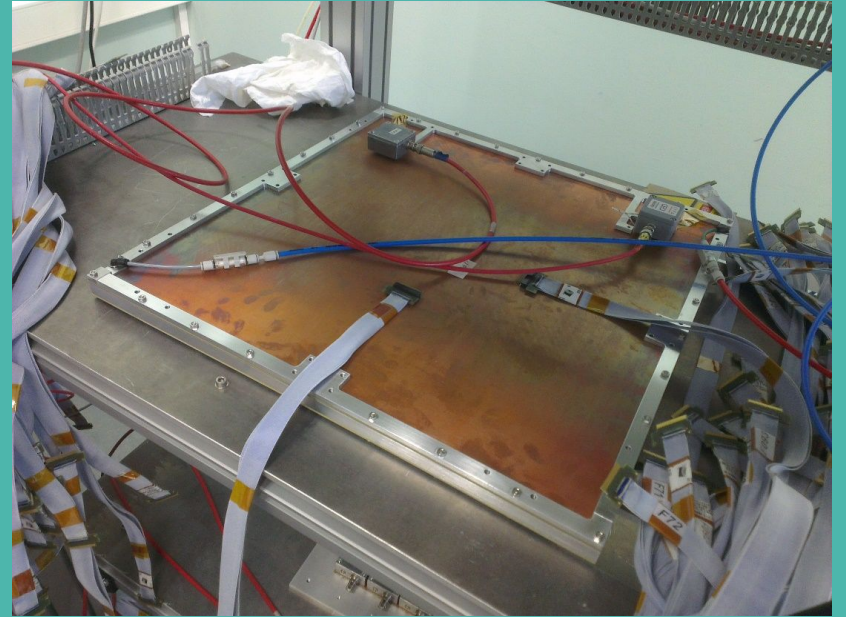


# Micromegas R&D for muon imaging activities at Saclay

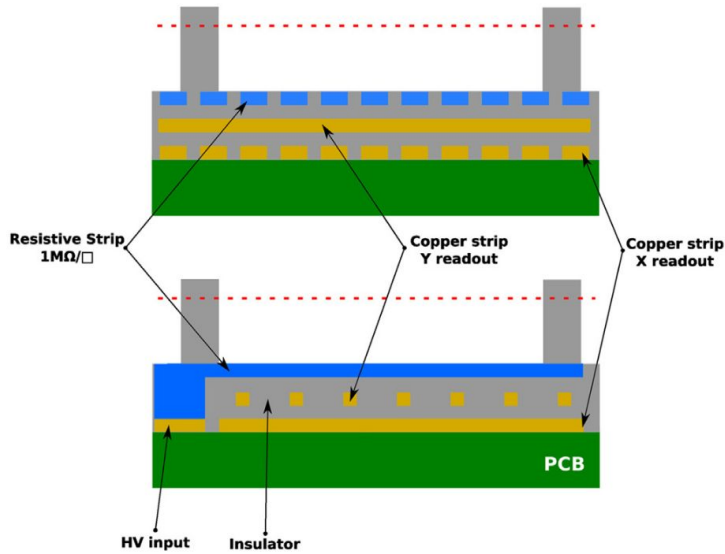
Christopher Filosa  
(CEA/DRF/IRFU/DPhN)



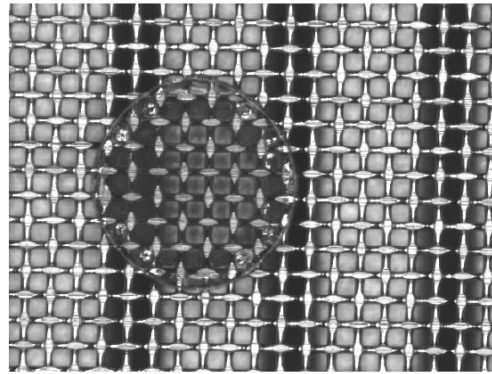
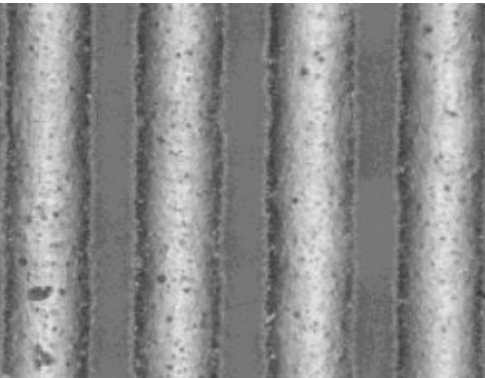
# MicroMegas at Saclay



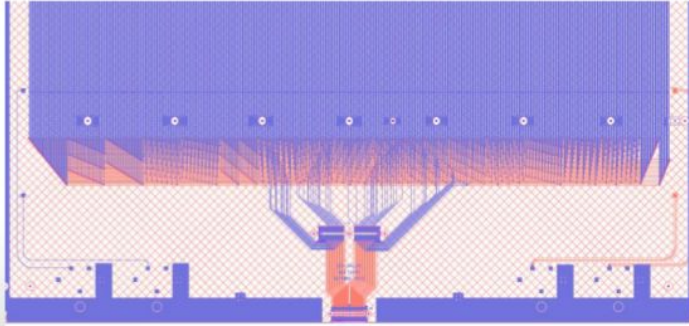
# 2D Readout bulked resistive Micromegas



- 50 x 50 cm<sup>2</sup> active surface
- 3 strip layers
  - resistive (X) (482 μm pitch and 380 μm strips)
  - Y readout (482 μm pitch and 100 μm strips)
  - X readout (482 μm pitch and 380 μm strips)
- Bulk technology
- Resistive ink spread on PCB
  - Serigraphic process
  - Integrated resistivity ~ few hundred of kΩ



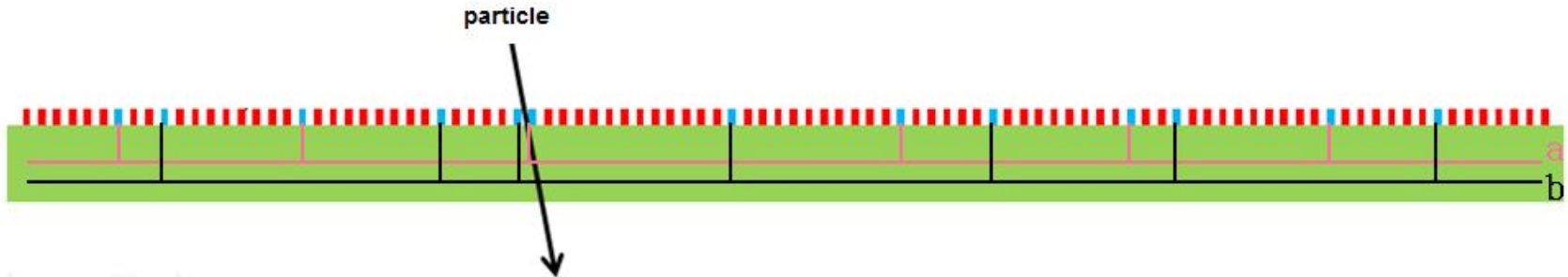
# Genetic multiplexing



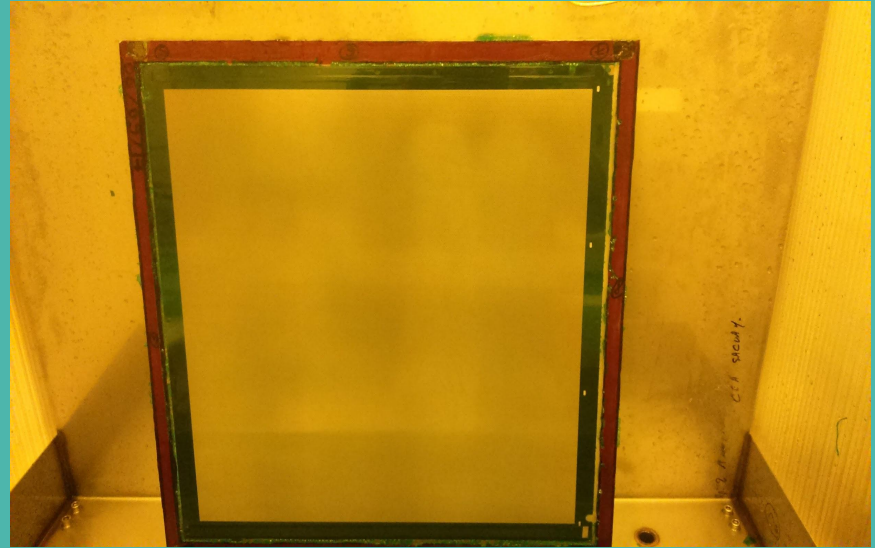
Multiplexing layout

Reduction of costs and simplified electronic output

- 1037 strips read by 61 channels (reduction factor 17)
- Doublet of channel are connected to a unique doublet of consecutive strips
- Use signal spread over strips
- Multiplexing factor is adjustable w.r.t. flux inside the detector

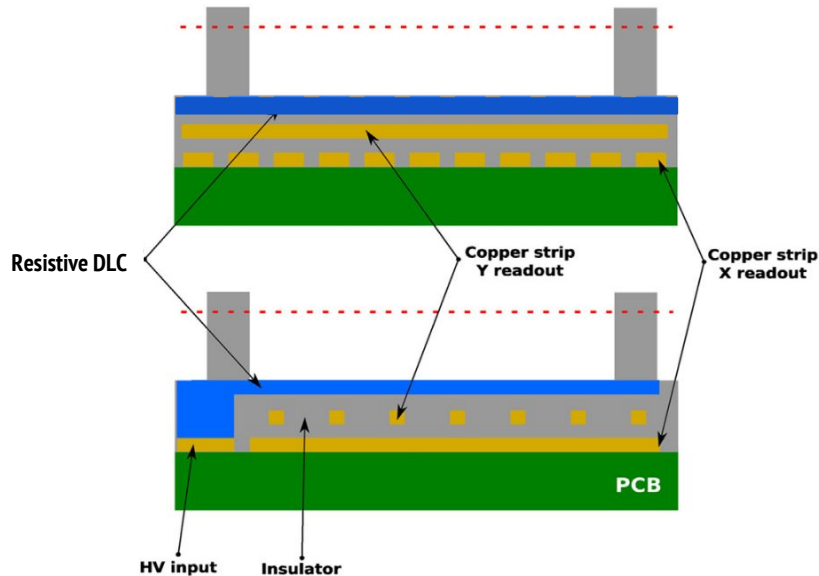


# Micromegas R&D



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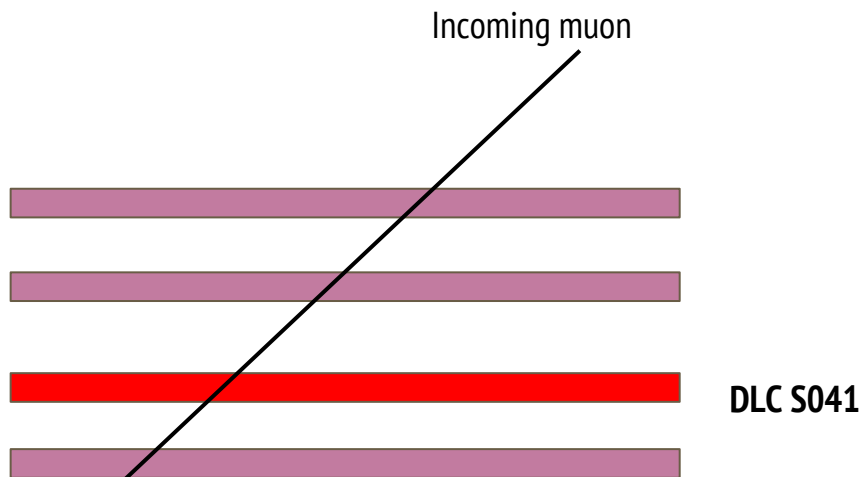
# Diamond Like Carbon (DLC) Micromegas



- 50 x 50 cm<sup>2</sup> active surface
- Resistive DLC
  - Chemical deposition technique
  - No alignment needed
  - More homogeneous than strips
  - Pressed and glued by Rui de Oliveira at CERN
  - Bulked at Saclay
- Integrated resistivity ~ 50M $\Omega$ 
  - higher than resistive strips
  - Clusters' size are expected to be equal in X/Y readout

# Characterization of DLC Micromegas

## Experimental set up (1)



DLC Micromegas  
Serigraphic Micromegas

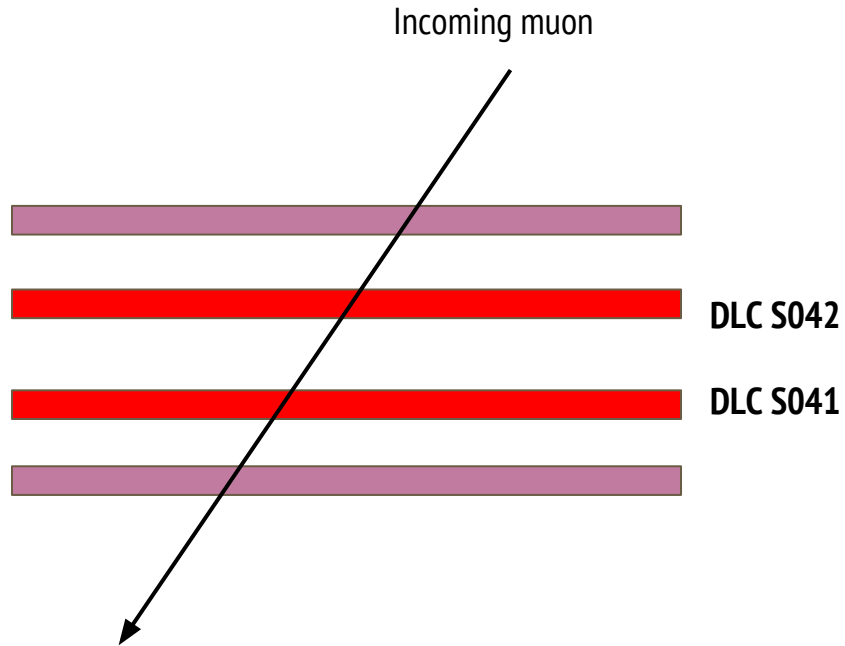


DLC characterised in TomoMu



# Characterization of DLC Micromegas

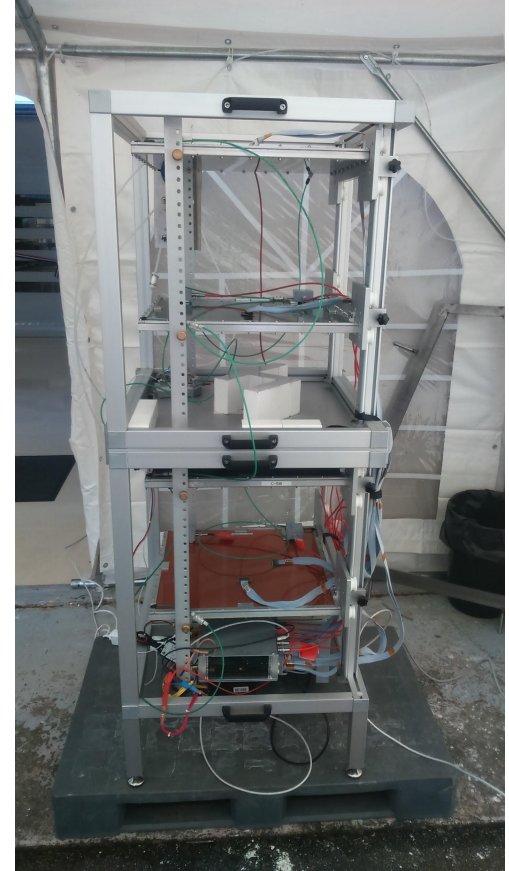
## Experimental set up (2)



DLC Micromegas  
Serigraphic Micromegas



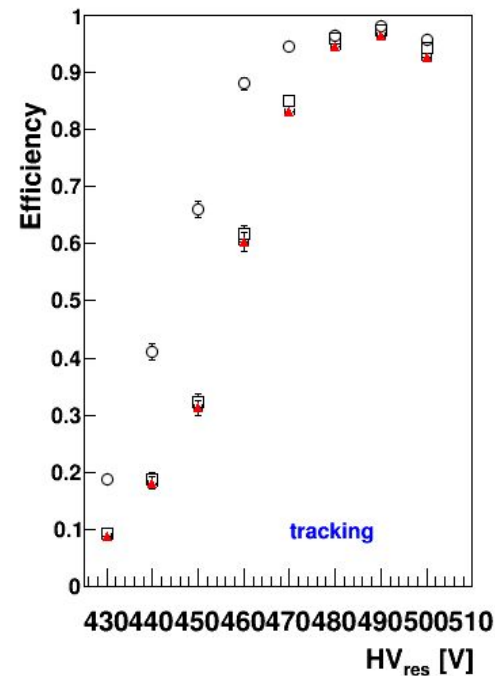
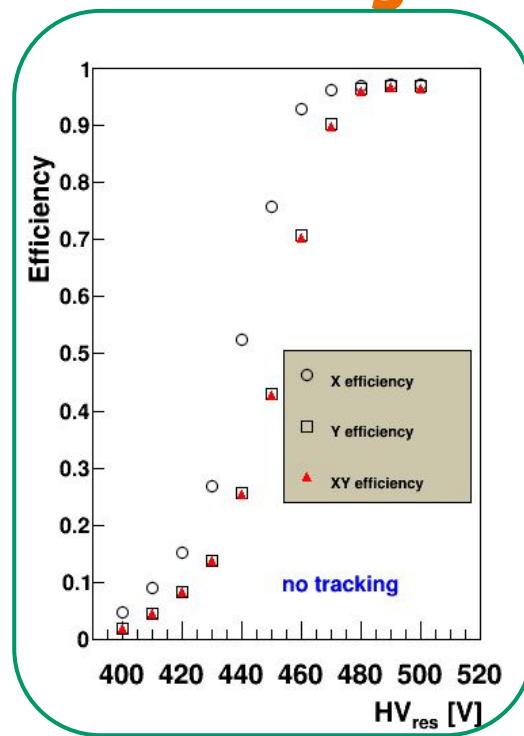
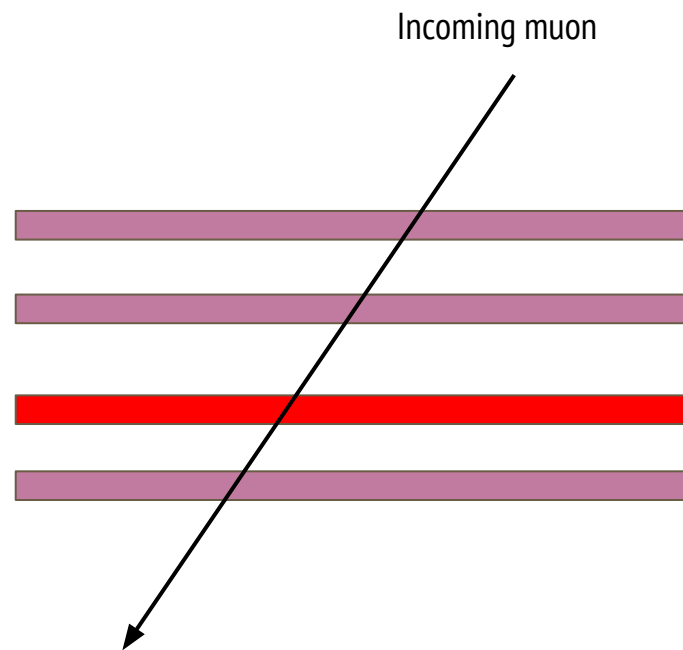
DLC characterised in TomoMu





# Characterization of DLC Micromegas

## Efficiency plateau



Nb of events on the DLC / Total nb of events

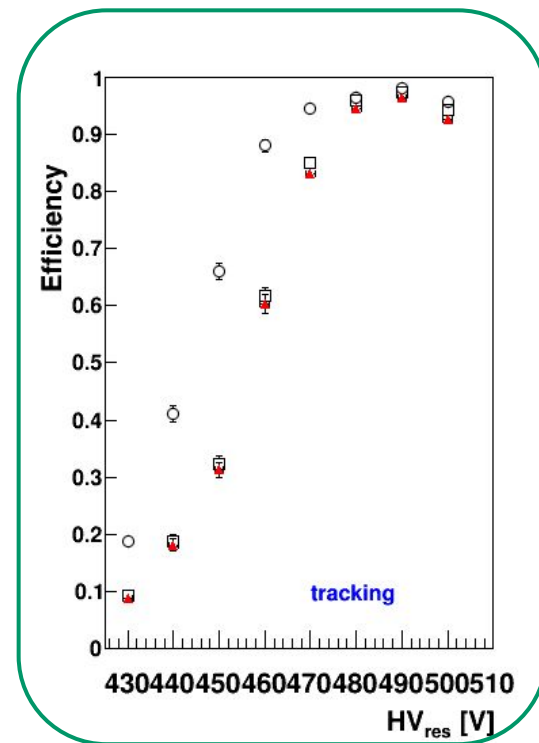
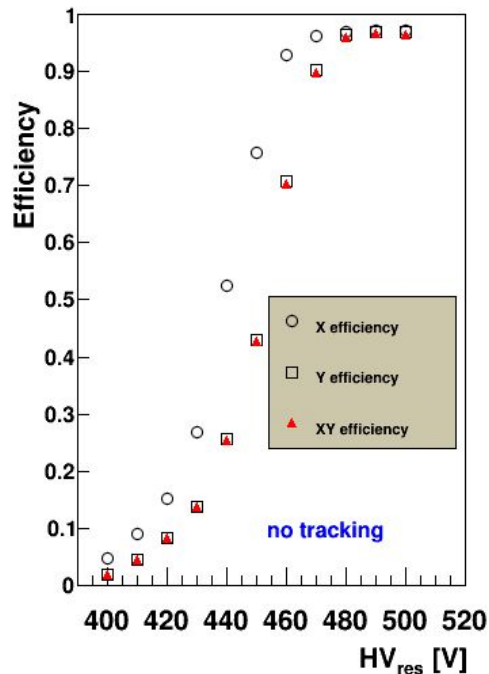
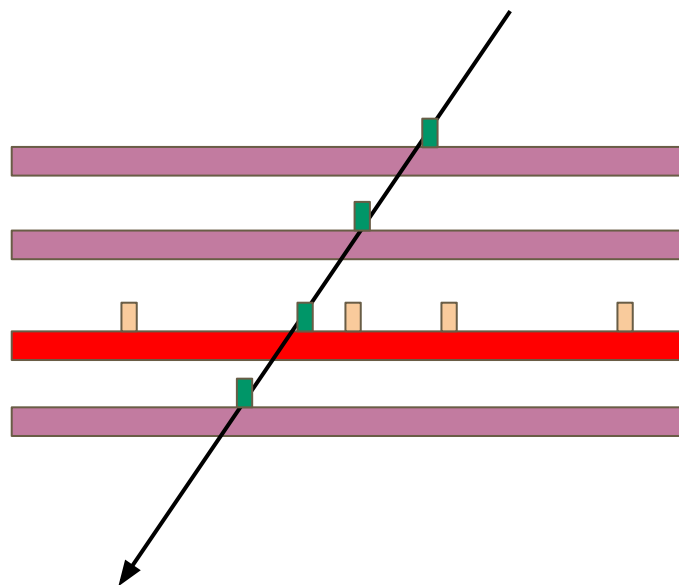
DLC Micromegas  
Serigraphic Micromegas



# Characterization of DLC Micromegas

## Efficiency plateau

Incoming muon



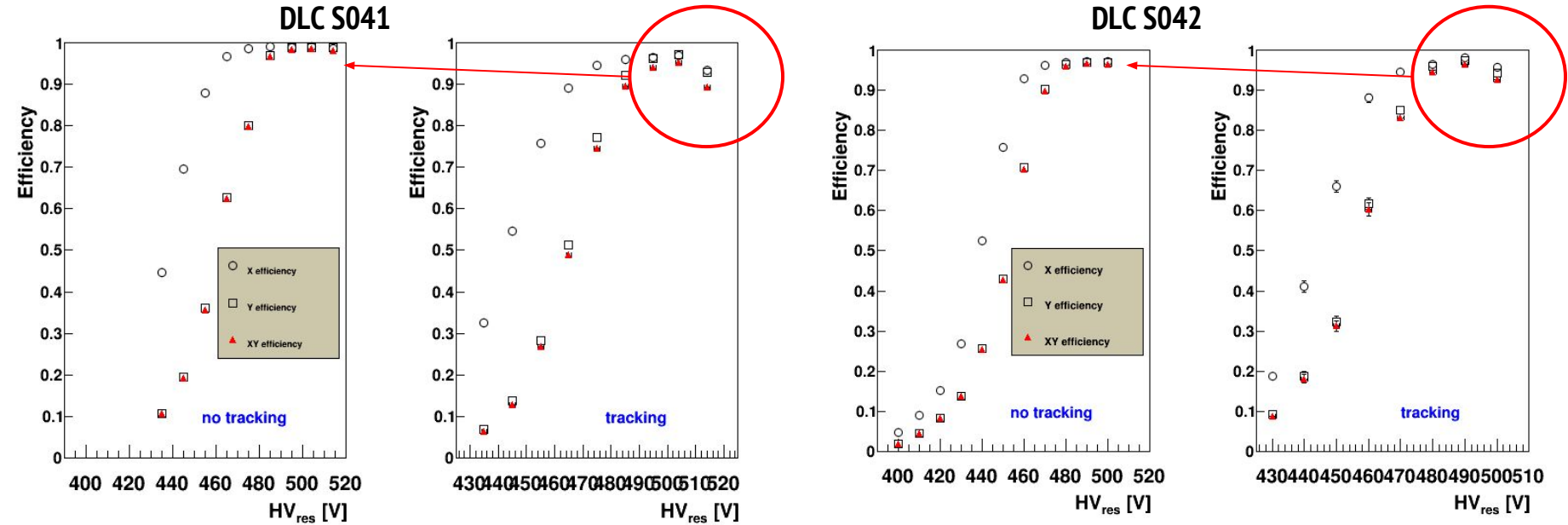
Nb of well reconstructed events on the DLC (Cluster near the reconstructed track)/  
Total nb of reconstructed events

DLC Micromegas  
Serigraphic Micromegas



# Characterization of DLC Micromegas

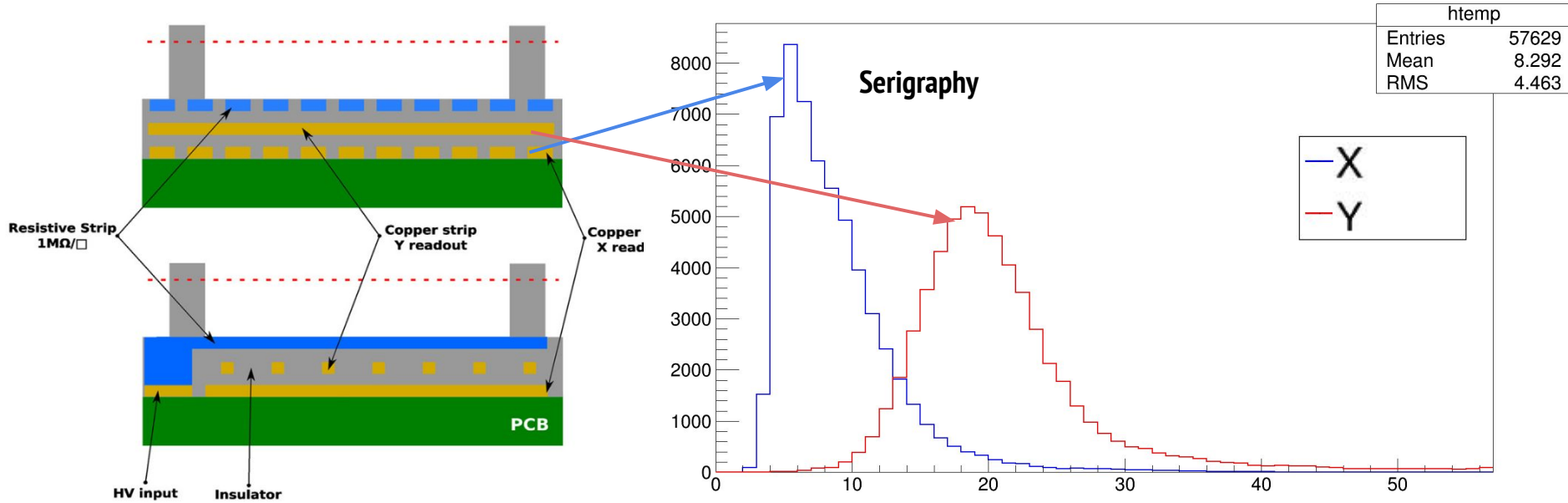
Efficiency plateau (gas Ar:95 iC<sub>4</sub>H<sub>10</sub>:5)



Observable differences between tracking and no tracking efficiency plateau -> Need more investigations

# Characterization of DLC Micromegas

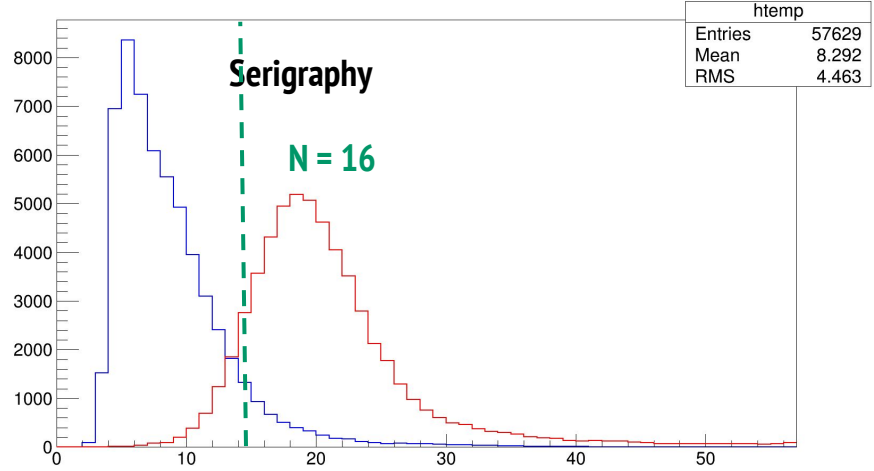
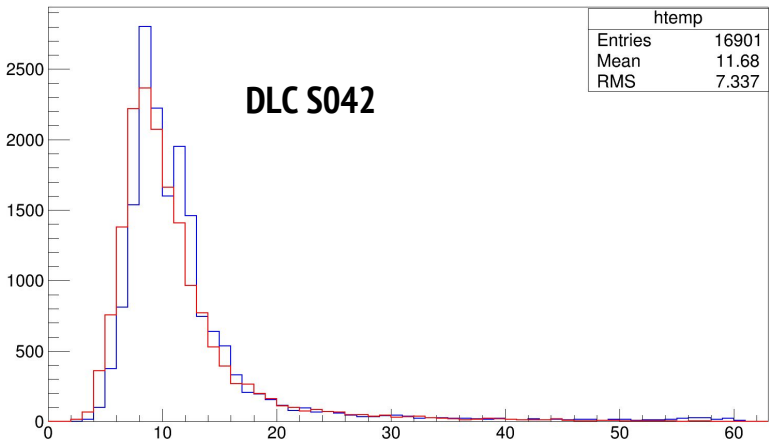
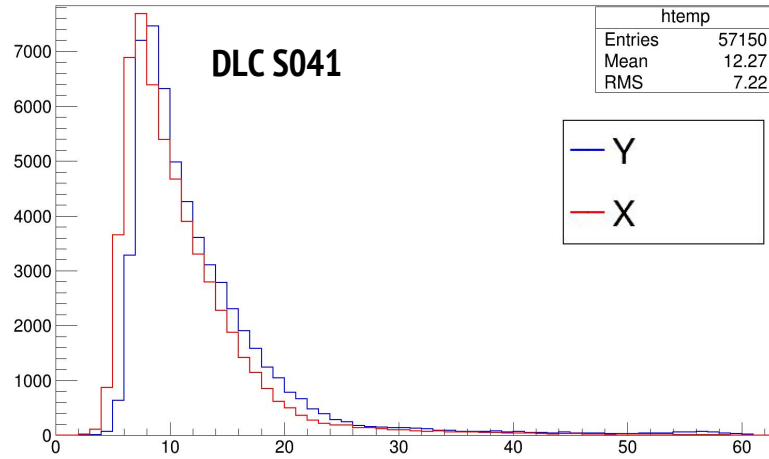
## Cluster size distribution



- Increasing of clusters' size due to the position of Y strips (Charge collection along the resistive strips)

# Characterization of DLC Micromegas

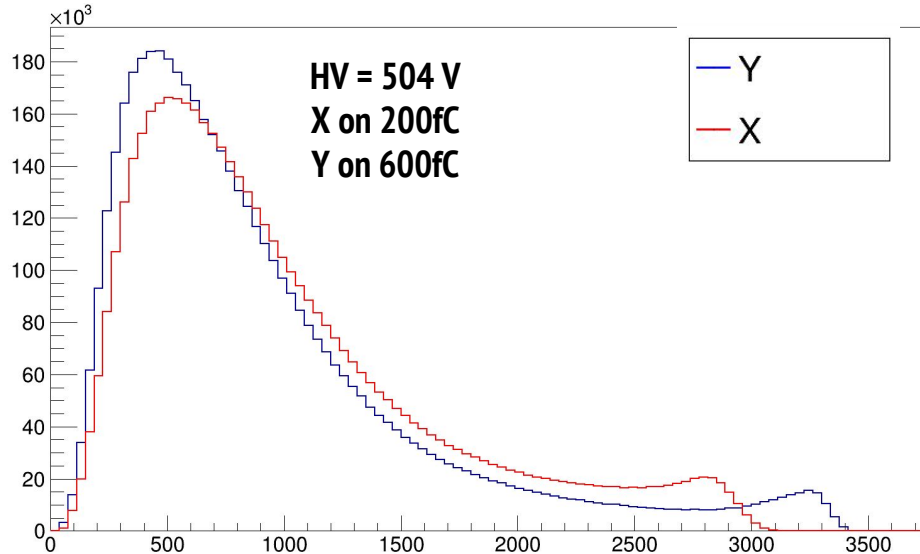
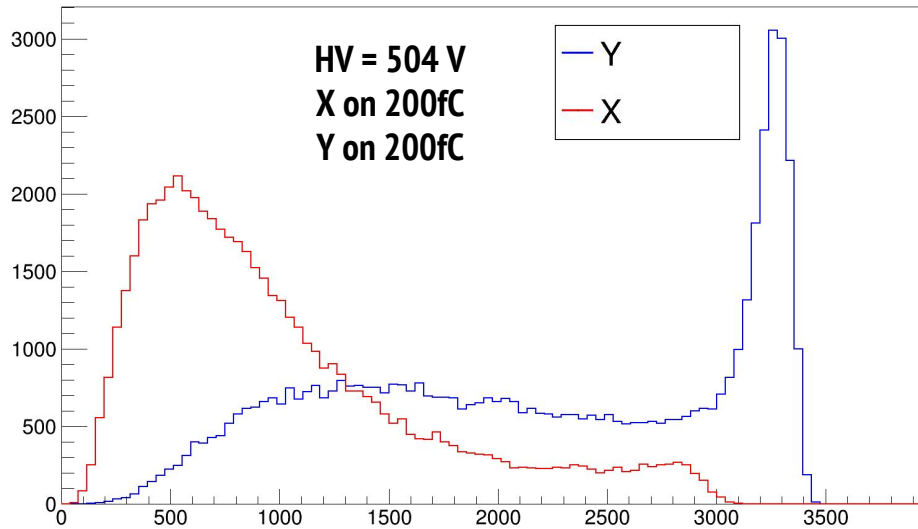
## Cluster size distribution



- For cluster size >16
  - Ambiguities can appear
  - Spatial resolution degraded
  - Need to improve X coordinate
- Higher resistivity for DLC + no strips structure
  - Less spreading
  - DLC Clusters' size are equal in X/Y

# Characterization of DLC Micromegas

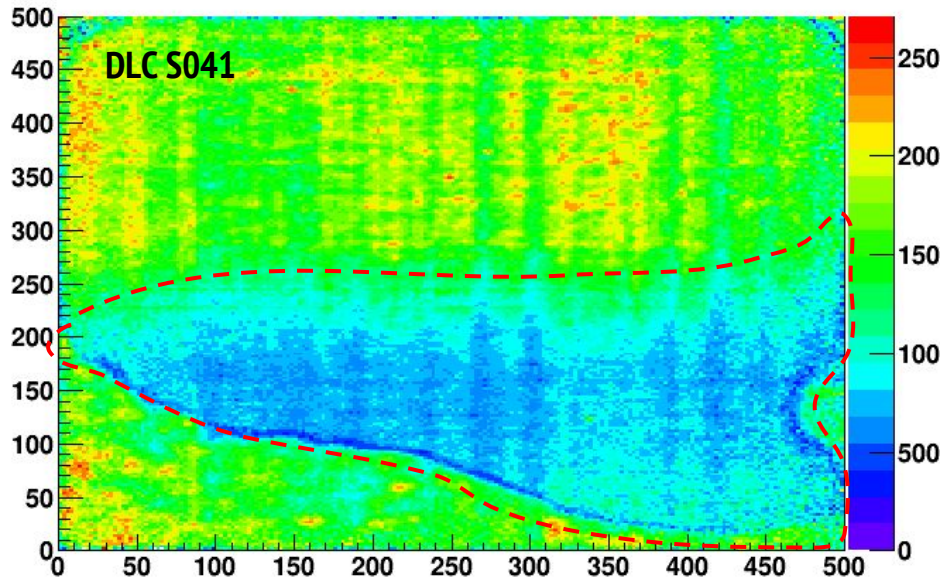
## Amplitude distribution S041



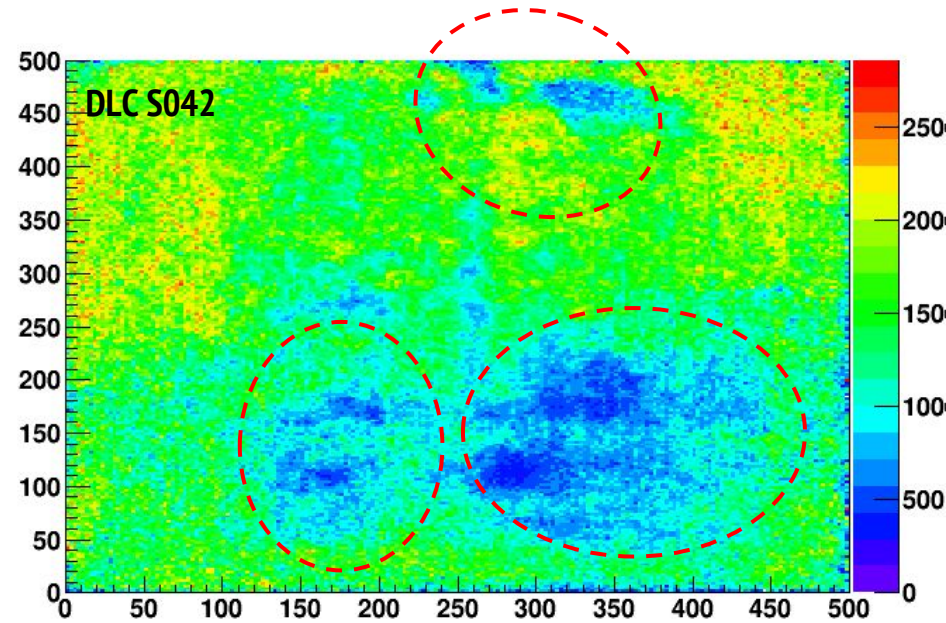
- Charge mostly received by upper strips  
→ Factor 3 between Y (up) and X (down) strips

# Characterization of DLC Micromegas

## 2D Map of amplitude



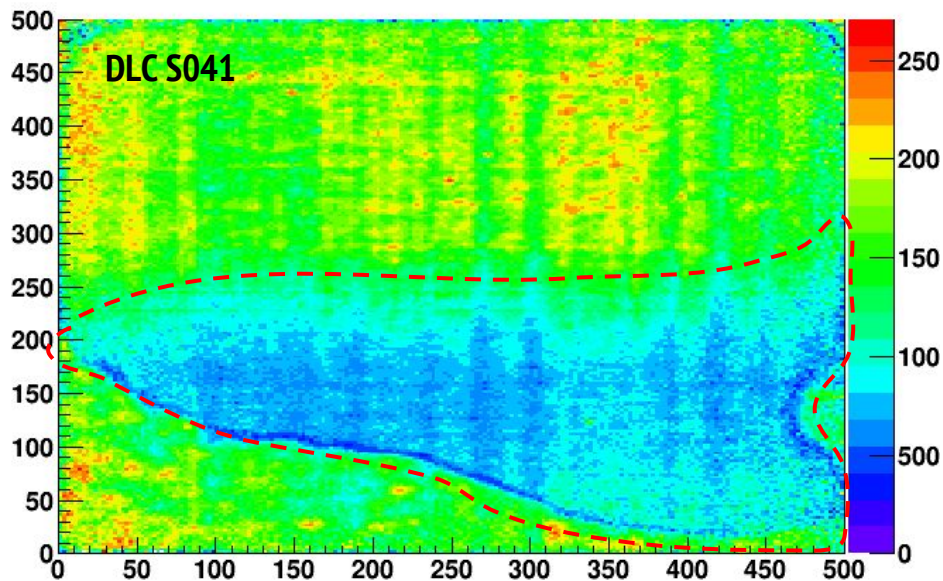
- Problem during bulk process  
→ Unstuck pillars zone
- Nevertheless, the unstuck zone is still efficient when the HV increases



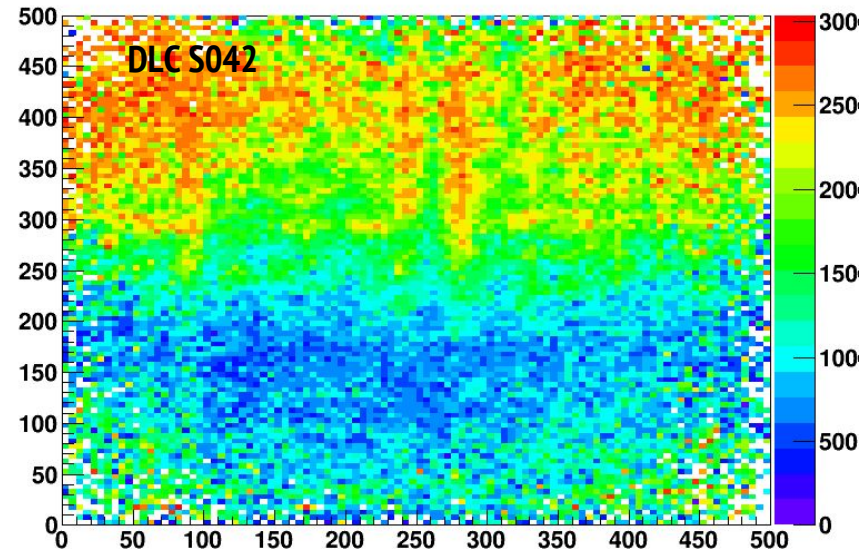
- No problem with pillars
- Inhomogeneous zone of gain
- Problem during cleaning process  
→ Development bath  
→ Remnant of photoresist film

# Characterization of DLC Micromegas

## 2D Map of amplitude



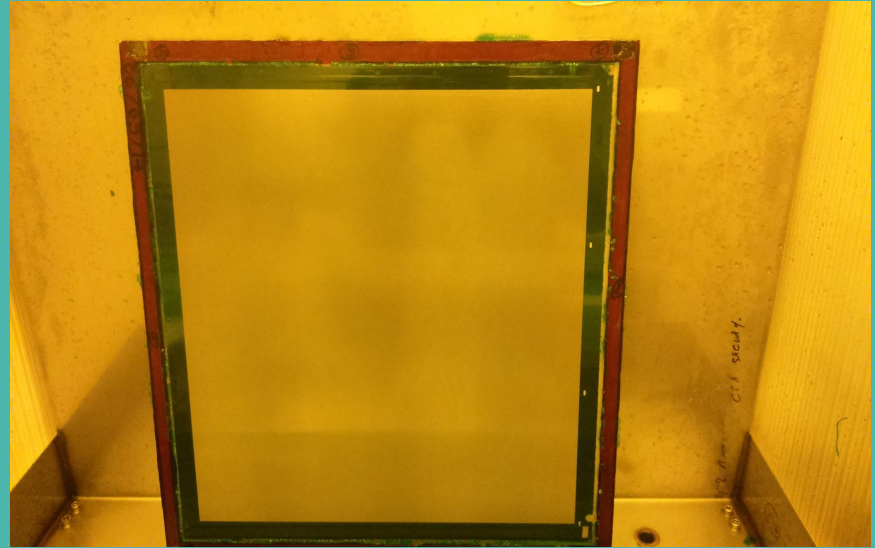
- Problem during bulk process  
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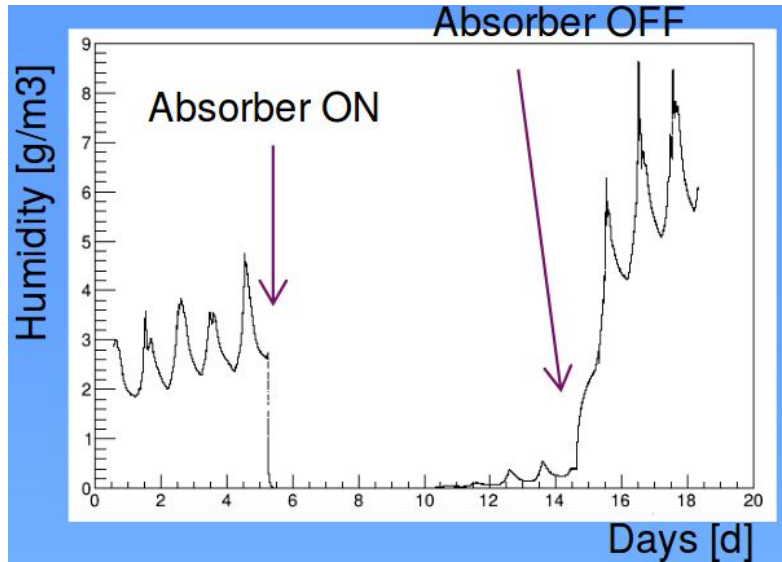
- Still Inhomogeneous zone of gain after alcohol + karcher
- Deposit of photoresist film?(change of mesh color observed)



# Gas R&D

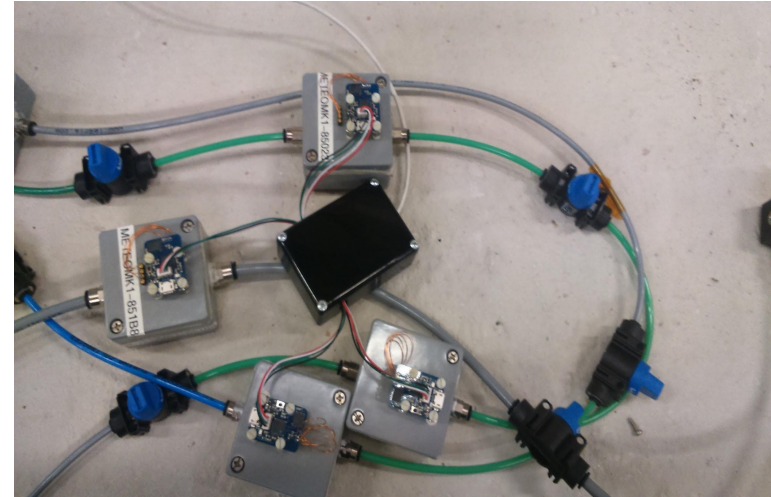
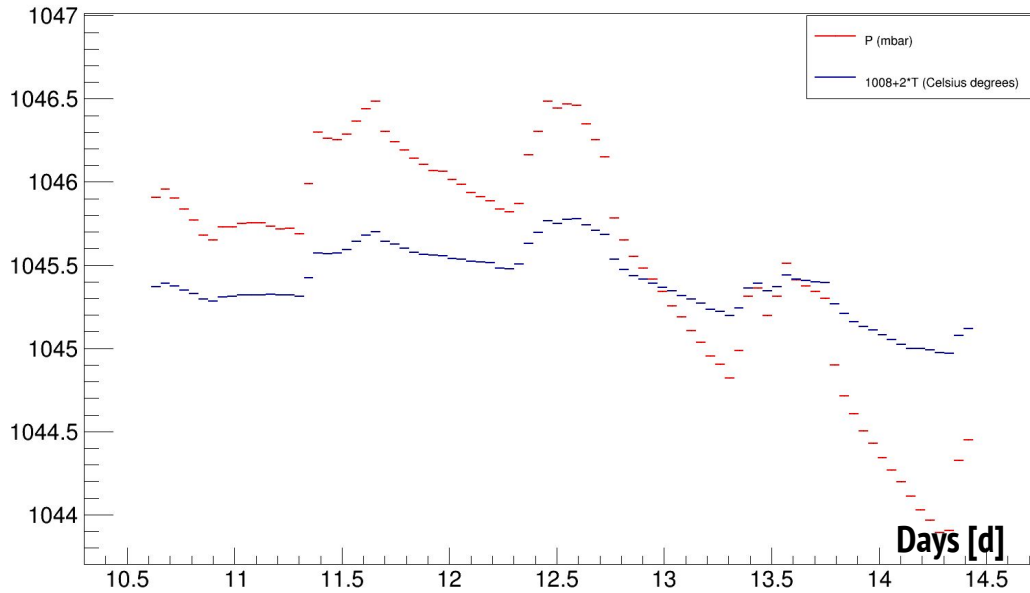


# Problem of outgassing



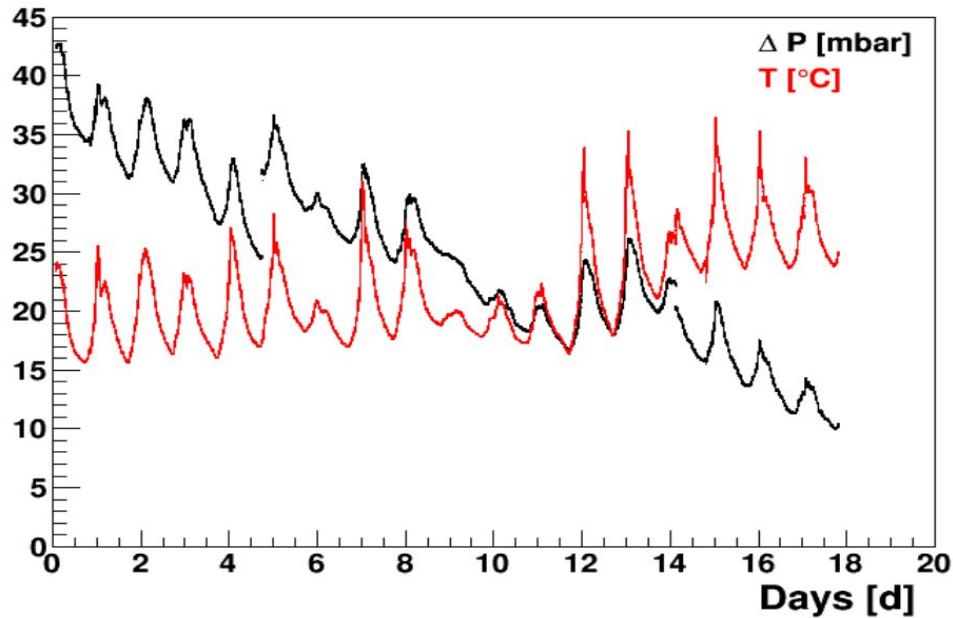
- PCB outgassing issue
  - Humidity + gaseous pollutant through the outgassing of PCB
  - Degradation of gas : Recirculation + purification system
  - To be tested : Heated process for PCB (à la HARPO) or protected PCB with varnish
  - New vacuum chamber to make tests

# Reducing gas leaking (sensors' box)



- Test of valves + flexible pipes + boxes containing H/P/T sensors
  - 7 sensors, each in independent box
  - 14 days of data taking (not continuously)
  - Volume =  $5*5*2.5 = 62.5\text{cm}^3$
  - Overpressure = 50 mbar
  - Leak =  $9.3 \cdot 10^{-4} \text{ mL/h} < 1 \mu\text{L/h}$

# Reducing gas leaking (detector)



- Best detectors = 0.3ml/h
- Idea : Sealed detector to reduce drastically the leak of gas
- Need to controle T
- Electronic control of gas consumption (2 to 3 times less)



# Recap

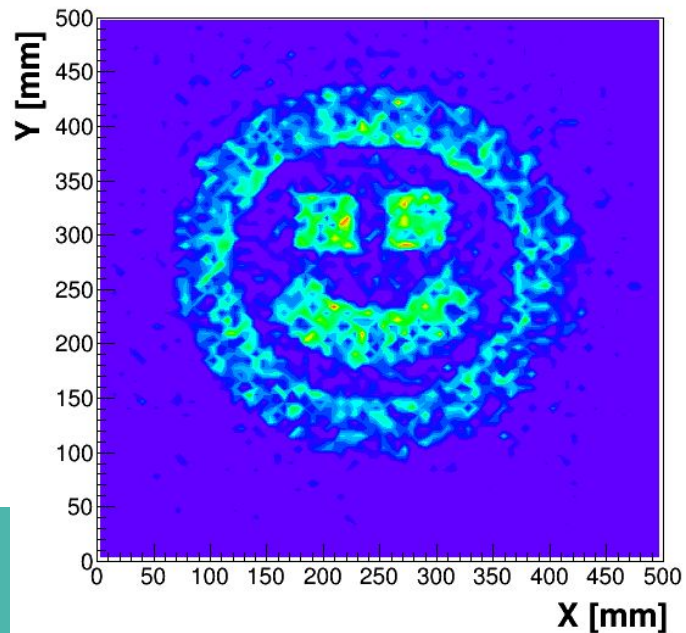
- **More R&D on DLC**

- Understand the inefficiency zones which appeared on the DLC (glue, remnant of photoresist ?)
- Choose between two technologies (serigraphy or DLC)
- Make sure the spatial and time resolution are improved to plan  $\mu$ TPC algorithm

- **Prospectives**

- Build 4 layers telescope with reduced gas leaking + electronic gas management
- Build 4 layers telescope in a sealed mode (eg: geophysics applications), after outgassing R&D

# THANKS



DE LA RECHERCHE À L'INDUSTRIE

**cea**

